

1.1 Scope.

This specification covers the detail requirements for a high speed sample-and-hold amplifier.

1.2 Part Number.

The complete part number per Table 1 of this specification is as follows:

| Device | Part Number |
|--------|--------------|
| –1 | AD346SD/883B |

1.2.3 Case Outline.

See Appendix 1 of General Specification ADI-H-1000; package outline: DH-14A

1.3 Absolute Maximum Ratings. ($T_A = +25^{\circ}\text{C}$ unless otherwise noted)

| | |
|------------------------------------|-----------------|
| +V _{CC} to GND (Pin 11) | +18V |
| –V _{CC} to GND (Pin 14) | –18V |
| Digital Input (Pin 1) | 0 to +7V |
| Analog Input (Pin 13) | ±15V |
| Junction Temperature | +175°C |
| Storage Temperature Range | –65°C to +150°C |
| Lead Temperature (Soldering 10sec) | +300°C |

1.5 Thermal Characteristics.

Thermal Resistance $\theta_{JC} = 20^{\circ}\text{C/W}$
 $\theta_{JA} = 60^{\circ}\text{C/W}$

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Table 1.

| Test | Symbol | Device | Design Limit @ +25°C | Sub Group 1 | Sub Group 2, 3 | Sub Group 4 | Test Condition ¹ | Units |
|----------------------------------------------|--------------|--------|-------------------------|-------------------|----------------------|-------------------|-----------------------------|------------------------|
| Analog Input Voltage Range | V_{IN} | -1 | 10 | | | 10 | | $\pm V_{min}$ |
| Overvoltage, No Damage | V_{OV} | -1 | 15 | | | | | $\pm V_{max}$ |
| Digital Input Logic "1" Current | I_{IH} | -1 | 20 | | | | | μA_{max} |
| Digital Input Logic "0" Current | I_{IL} | -1 | 360 | | | | | $-\mu A_{max}$ |
| Digital Input Track Mode Logic "1" | V_{IH} | -1 | 2.0 5.5 | | | | | V_{min} V_{max} |
| Digital Input Hold Mode Logic "0" | V_{IL} | -1 | 0 0.8 | | | | | V_{min} V_{max} |
| Analog Output Voltage ² | V_O | -1 | 10.0 | | | 10.0 | | $\pm V_{min}$ |
| Offset Voltage ³ | V_{OS} | -1 | 3 | 3 | | | | $\pm mV_{max}$ |
| Offset Voltage Temperature Coefficient | V_{OSTC} | -1 | 20 | | 20 | | | $\pm mV_{max}$ |
| Gain Error | A_E | -1 | 0.02 | 0.02 | | | % of -1V/V | $\pm \%_{max}$ |
| Gain Error Over Temperature | $TC A_E$ | | 0.05 | | 0.05 | | % of -1V/V | $\pm \%_{max}$ |
| Offset Step (Pedestal) | O_S | -1 | 4 | 4 | | | | $\pm mV_{max}$ |
| Pedestal Over Temperature | $TC O_S$ | -1 | 20 | | 20 | | | $\pm mV_{max}$ |
| Droop Rate | T_{DR} | -1 | 0.5 | 0.5 | | | | mV/ms_{max} |
| Droop Rate over Temperature | T_{DRTC} | -1 | 650 | | 650 | | | mV/ms_{max} |
| Acquisition Time to $\pm 0.01\%$ 10V Step | t_{A1} | -1 | 2.0 | | | | | μs_{max} |
| Acquisition Time to $\pm 0.01\%$ 20V Step | t_{A2} | -1 | 2.5 | | | 2.5 | | μs_{max} |
| Settling Time Sample Mode | t_{S1} | -1 | 2.0 | | | | | μs_{max} |
| Sample to Hold | t_{S2} | -1 | 1.0 | | | | | μs_{max} |
| Feedthrough (Hold Mode) | FT | -1 | 0.02 | | | 0.02 | @ $C_L \leq 200pF$ | % FSR $_{max}$ |
| Nominal Voltages for Rated Performance | V_S | -1 | 15 | | | | ($\pm 3\%$) | $\pm V_{typ}$ |
| Power Supply Rejection Ratio | PSRR | -1 | 300 | | | | | $\mu V/V_{max}$ |
| Supply Currents | + I_{SS} | -1 | 18 | 18 | | | $V_{SS} = \pm 15V$ | mA_{max} |
| | - I_{SS} | -1 | 10 | 10 | | | $V_{SS} = \pm 15V$ | $-mA_{max}$ |
| Supply Currents Over Temperature | + I_{SSTC} | -1 | 20 | | 20 | | $V_{SS} = \pm 15V$ | mA_{max} |
| | - I_{SSTC} | -1 | 10 | | 10 | | $V_{SS} = \pm 15V$ | $-mA_{max}$ |

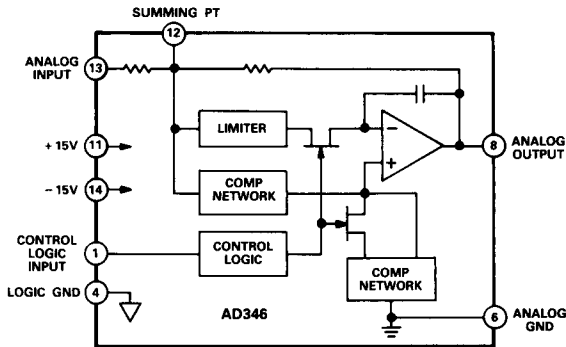
NOTES

¹ $T_A = +25^\circ C$ and $\pm V_S = \pm 15V$ unless otherwise specified.

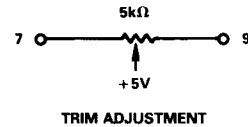
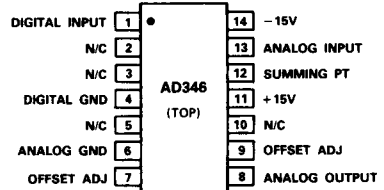
²Max Output Swing is 4V less than $+V_S$.

³Voltage Offset is externally adjustable to zero.

3.2.1 Functional Block Diagram and Terminal Assignments.



DH-14A Package



3.2.4 Microcircuit Technology Group.

This microcircuit is covered by technology group (I).

4.2.1 Life Test/Burn-In Circuit.

Steady state life test is per MIL-STD-883 Method 1005. Burn-in is per MIL-STD-883 Method 1015 test condition (B).

